www.SeCosGmbH.com

Headquarter Address:
8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
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Product/Process Change Notification

PCN#	Effective Date	Issue Date
2015-11-01C-01	2016/2/1	2015/11/1

PCN Classification	Product Category
Major	MOSFET

Subject

Change the assembly house.

Affected Product(s)

SSM0410

Description of Change(s)

The original assembly house, GTM Corporation, was shut down; thus, we change to the second assembly house.

Content of Change(s)

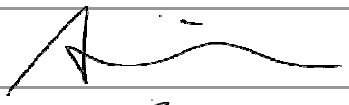
Assembly house.

Impact(s)

None

Attachment(s)

Reliability Test Report.

Approval		
Issued by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu
Customer Approval		
Customer's Comment		
Customer's Consent with Signature		

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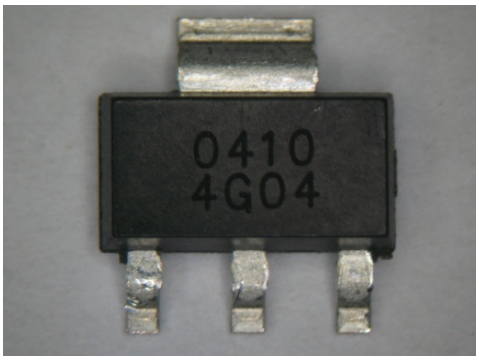
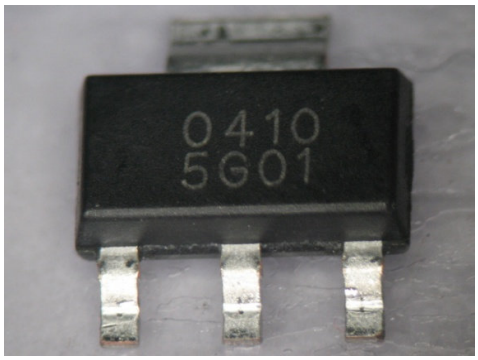
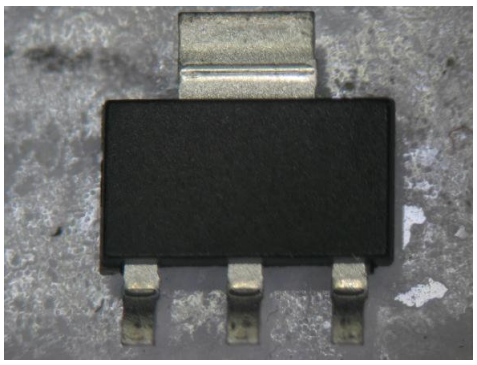
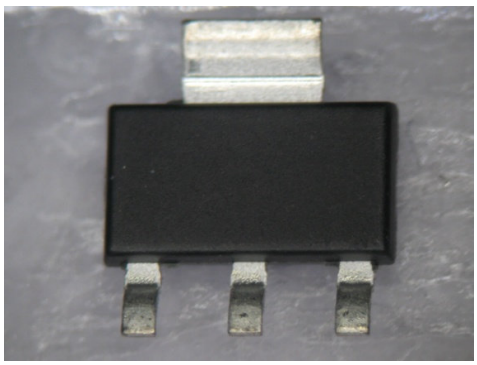
Exterior Comparison Chart	
Original	New
 Top View	 Top View
 Back View	 Back View

SeCoS Corporation

Reliability Testing Summary Report

Date: 2015/10/08 Document No.: SI15 -10-113

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SSM0410	100 ± 5℃, 80%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SSM0410	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SSM0410	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SSM0410	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SSM0410	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SSM0410	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	SSM0410	245 ± 5℃, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2015.08.17 Testing End Date: 2015.10.08

Tester: King Huang Approval: Peter Yang

SeCoS Corporation

Electrical Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 25℃
Test Date: 2015.08.17
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	112.2V	0.053uA	128.7mΩ
2	112.4V	0.058uA	128.7mΩ
3	111.8V	0.061uA	128.6mΩ
4	111.4V	0.059uA	129.3mΩ
5	111.8V	0.053uA	128.8mΩ
6	111.8V	0.065uA	128.9mΩ
7	111.7V	0.043uA	128.5mΩ
8	111.7V	0.044uA	129.2mΩ
9	111.8V	0.046uA	128.3mΩ
10	111.5V	0.052uA	128.9mΩ
11	112.0V	0.041uA	129.1mΩ
12	112.1V	0.052uA	129.0mΩ
13	112.1V	0.063uA	128.5mΩ
13	111.7V	0.062uA	129.3mΩ
15	112.3V	0.053uA	128.4mΩ
16	111.5V	0.061uA	129.1mΩ
17	111.6V	0.040uA	129.0mΩ
18	111.4V	0.057uA	128.3mΩ
19	111.6V	0.043uA	129.1mΩ
20	111.6V	0.048uA	128.3mΩ
21	112.1V	0.055uA	129.1mΩ
22	112.2V	0.046uA	129.1mΩ
23	111.6V	0.053uA	128.6mΩ
24	111.4V	0.051uA	129.3mΩ
25	111.4V	0.053uA	129.1mΩ
26	111.8V	0.061uA	129.3mΩ
27	112.3V	0.053uA	128.9mΩ
28	111.5V	0.059uA	128.5mΩ
29	111.7V	0.050uA	129.1mΩ
30	112.3V	0.064uA	129.1mΩ

SeCoS Corporation

Electrical Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 25℃
Test Date: 2015.08.17
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
31	111.7V	0.044uA	128.5mΩ
32	112.4V	0.060uA	129.3mΩ
33	111.5V	0.050uA	128.8mΩ
34	111.8V	0.042uA	129.0mΩ
35	112.0V	0.041uA	128.5mΩ
36	112.2V	0.052uA	129.2mΩ
37	111.8V	0.056uA	128.4mΩ
38	111.7V	0.052uA	129.3mΩ
39	111.6V	0.065uA	129.0mΩ
40	112.0V	0.058uA	128.5mΩ
41	112.1V	0.064uA	129.3mΩ
42	112.1V	0.057uA	128.6mΩ
43	111.4V	0.055uA	128.9mΩ
44	111.7V	0.043uA	129.0mΩ
45	111.4V	0.040uA	128.9mΩ
46	112.1V	0.041uA	128.2mΩ
47	112.0V	0.043uA	129.3mΩ
48	112.0V	0.063uA	128.5mΩ
49	111.8V	0.046uA	128.6mΩ
50	111.4V	0.043uA	128.7mΩ
51	111.4V	0.045uA	128.6mΩ
52	111.6V	0.042uA	128.6mΩ
53	111.9V	0.052uA	128.7mΩ
54	111.7V	0.055uA	128.9mΩ
55	112.3V	0.050uA	129.4mΩ
56	111.7V	0.043uA	128.7mΩ
57	111.7V	0.045uA	128.6mΩ
58	112.2V	0.054uA	128.3mΩ
59	112.3V	0.053uA	128.7mΩ
60	111.7V	0.061uA	128.2mΩ

SeCoS Corporation

Electrical Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 25℃
Test Date: 2015.08.17
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
61	112.0V	0.053uA	128.4mΩ
62	111.7V	0.044uA	128.7mΩ
63	112.3V	0.048uA	128.8mΩ
64	112.2V	0.053uA	129.3mΩ
65	112.1V	0.064uA	128.9mΩ
66	112.3V	0.041uA	128.9mΩ
67	112.4V	0.049uA	129.4mΩ
68	112.0V	0.058uA	128.9mΩ
69	111.4V	0.063uA	128.9mΩ
70	111.9V	0.058uA	128.7mΩ
71	111.5V	0.040uA	128.3mΩ
72	112.0V	0.050uA	128.4mΩ
73	112.4V	0.063uA	128.9mΩ
74	111.5V	0.051uA	128.7mΩ
75	112.3V	0.049uA	129.3mΩ
76	111.7V	0.050uA	128.8mΩ
77	111.8V	0.053uA	129.2mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	111.7V	0.055uA	128.8mΩ	112.3V	0.046uA	128.7mΩ
2	111.7V	0.048uA	128.9mΩ	111.5V	0.061uA	128.8mΩ
3	112.4V	0.065uA	129.1mΩ	112.0V	0.058uA	129.3mΩ
4	112.4V	0.042uA	128.9mΩ	112.3V	0.042uA	129.2mΩ
5	112.3V	0.061uA	129.2mΩ	112.3V	0.049uA	128.9mΩ
6	111.5V	0.063uA	129.0mΩ	111.6V	0.051uA	129.0mΩ
7	111.9V	0.053uA	128.5mΩ	111.6V	0.059uA	128.2mΩ
8	111.6V	0.052uA	129.0mΩ	112.2V	0.040uA	129.1mΩ
9	112.1V	0.058uA	128.8mΩ	111.8V	0.063uA	129.0mΩ
10	111.5V	0.055uA	128.2mΩ	112.1V	0.047uA	128.5mΩ
11	111.9V	0.046uA	129.3mΩ	111.6V	0.046uA	129.1mΩ
12	111.8V	0.065uA	128.5mΩ	111.7V	0.057uA	128.4mΩ
13	112.3V	0.064uA	129.1mΩ	112.0V	0.056uA	129.2mΩ
13	111.5V	0.052uA	129.3mΩ	111.5V	0.051uA	128.4mΩ
15	111.6V	0.046uA	128.5mΩ	111.7V	0.063uA	129.3mΩ
16	111.8V	0.049uA	129.0mΩ	112.1V	0.059uA	128.8mΩ
17	111.7V	0.053uA	128.7mΩ	112.2V	0.040uA	128.8mΩ
18	112.4V	0.055uA	129.2mΩ	111.4V	0.052uA	128.6mΩ
19	111.6V	0.046uA	129.1mΩ	112.3V	0.055uA	129.1mΩ
20	112.4V	0.056uA	128.4mΩ	112.0V	0.056uA	128.4mΩ
21	111.8V	0.041uA	128.9mΩ	112.2V	0.054uA	129.2mΩ
22	111.7V	0.049uA	129.1mΩ	111.5V	0.043uA	129.4mΩ
23	111.8V	0.054uA	128.8mΩ	111.6V	0.042uA	128.2mΩ
24	112.2V	0.064uA	128.7mΩ	112.2V	0.040uA	129.2mΩ
25	112.3V	0.058uA	128.4mΩ	111.7V	0.061uA	129.1mΩ
26	111.6V	0.047uA	128.8mΩ	111.7V	0.064uA	128.5mΩ
27	112.0V	0.053uA	128.9mΩ	111.6V	0.042uA	129.3mΩ
28	111.7V	0.064uA	128.3mΩ	111.8V	0.045uA	129.0mΩ
29	112.0V	0.043uA	128.2mΩ	112.3V	0.054uA	128.8mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	111.4V	0.063uA	128.7mΩ	112.3V	0.055uA	129.3mΩ
31	111.6V	0.048uA	129.4mΩ	112.2V	0.040uA	129.0mΩ
32	112.2V	0.049uA	129.3mΩ	111.5V	0.045uA	128.9mΩ
33	111.9V	0.063uA	128.7mΩ	111.5V	0.049uA	128.7mΩ
34	112.3V	0.048uA	128.8mΩ	111.4V	0.043uA	128.7mΩ
35	111.4V	0.058uA	129.0mΩ	111.5V	0.043uA	129.0mΩ
36	112.3V	0.055uA	128.8mΩ	111.5V	0.046uA	128.3mΩ
37	111.6V	0.056uA	129.3mΩ	111.7V	0.049uA	128.3mΩ
38	112.2V	0.064uA	129.1mΩ	111.6V	0.048uA	128.3mΩ
39	111.6V	0.064uA	129.1mΩ	111.7V	0.055uA	129.4mΩ
40	111.8V	0.063uA	128.9mΩ	112.0V	0.045uA	128.7mΩ
41	111.6V	0.045uA	128.9mΩ	112.0V	0.053uA	128.3mΩ
42	111.9V	0.061uA	128.6mΩ	111.4V	0.048uA	128.3mΩ
43	111.6V	0.048uA	128.5mΩ	112.2V	0.061uA	129.2mΩ
44	112.2V	0.044uA	128.8mΩ	111.9V	0.060uA	128.6mΩ
45	111.5V	0.042uA	128.5mΩ	112.1V	0.057uA	129.3mΩ
46	111.5V	0.046uA	128.2mΩ	112.0V	0.049uA	129.0mΩ
47	112.1V	0.063uA	129.3mΩ	112.2V	0.042uA	129.1mΩ
48	111.5V	0.042uA	128.3mΩ	111.7V	0.057uA	128.4mΩ
49	111.8V	0.044uA	128.4mΩ	111.6V	0.062uA	128.6mΩ
50	112.3V	0.049uA	128.2mΩ	111.9V	0.058uA	129.0mΩ
51	111.7V	0.055uA	128.4mΩ	112.2V	0.061uA	129.0mΩ
52	112.4V	0.053uA	129.4mΩ	111.9V	0.058uA	128.9mΩ
53	111.5V	0.051uA	128.7mΩ	112.1V	0.043uA	128.7mΩ
54	111.4V	0.061uA	129.2mΩ	111.9V	0.056uA	128.5mΩ
55	112.4V	0.053uA	129.1mΩ	111.8V	0.056uA	128.8mΩ
56	112.0V	0.045uA	128.8mΩ	112.2V	0.064uA	128.8mΩ
57	111.6V	0.064uA	128.6mΩ	111.4V	0.053uA	128.9mΩ
58	112.0V	0.056uA	128.3mΩ	112.2V	0.045uA	129.1mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	111.5V	0.045uA	128.6mΩ	111.9V	0.045uA	129.4mΩ
60	111.4V	0.040uA	129.2mΩ	112.0V	0.057uA	129.2mΩ
61	112.2V	0.049uA	128.2mΩ	112.0V	0.057uA	128.9mΩ
62	111.5V	0.051uA	129.0mΩ	112.1V	0.055uA	129.1mΩ
63	112.1V	0.041uA	128.4mΩ	112.1V	0.061uA	129.1mΩ
64	112.0V	0.041uA	128.7mΩ	112.0V	0.046uA	129.0mΩ
65	112.3V	0.045uA	129.1mΩ	111.6V	0.048uA	129.2mΩ
66	112.2V	0.061uA	129.1mΩ	111.5V	0.041uA	128.8mΩ
67	111.9V	0.043uA	128.5mΩ	112.0V	0.041uA	129.0mΩ
68	111.8V	0.052uA	128.8mΩ	112.0V	0.048uA	129.2mΩ
69	111.7V	0.054uA	129.0mΩ	111.9V	0.048uA	129.1mΩ
70	111.8V	0.042uA	129.2mΩ	111.9V	0.055uA	128.2mΩ
71	112.2V	0.064uA	128.4mΩ	111.9V	0.042uA	128.7mΩ
72	111.8V	0.047uA	129.3mΩ	111.7V	0.048uA	128.5mΩ
73	112.4V	0.049uA	128.9mΩ	112.3V	0.053uA	129.2mΩ
74	111.9V	0.050uA	128.6mΩ	111.9V	0.043uA	129.1mΩ
75	112.0V	0.045uA	129.3mΩ	111.5V	0.065uA	129.2mΩ
76	112.2V	0.040uA	129.2mΩ	112.0V	0.041uA	128.7mΩ
77	111.7V	0.062uA	128.7mΩ	111.8V	0.060uA	129.1mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 150℃, 1000Hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	112.0V	0.045uA	128.3mΩ	111.7V	0.046uA	128.6mΩ
2	111.6V	0.042uA	128.8mΩ	112.2V	0.065uA	129.3mΩ
3	112.3V	0.054uA	129.3mΩ	112.3V	0.053uA	129.0mΩ
4	112.0V	0.056uA	129.0mΩ	112.2V	0.053uA	129.1mΩ
5	111.9V	0.064uA	128.3mΩ	111.8V	0.045uA	128.5mΩ
6	112.0V	0.050uA	128.5mΩ	112.2V	0.058uA	128.7mΩ
7	112.2V	0.052uA	129.1mΩ	112.3V	0.056uA	128.6mΩ
8	112.1V	0.047uA	128.2mΩ	112.3V	0.065uA	128.8mΩ
9	111.5V	0.059uA	129.3mΩ	111.4V	0.055uA	129.1mΩ
10	111.7V	0.051uA	128.6mΩ	112.2V	0.053uA	128.2mΩ
11	112.0V	0.057uA	129.3mΩ	111.9V	0.051uA	128.8mΩ
12	111.9V	0.047uA	129.3mΩ	112.2V	0.058uA	128.4mΩ
13	112.2V	0.050uA	128.5mΩ	111.8V	0.046uA	128.2mΩ
13	111.6V	0.064uA	129.1mΩ	112.0V	0.045uA	129.1mΩ
15	111.7V	0.059uA	128.4mΩ	112.2V	0.046uA	129.1mΩ
16	112.3V	0.059uA	129.2mΩ	112.2V	0.064uA	129.0mΩ
17	111.5V	0.061uA	128.5mΩ	112.1V	0.045uA	128.8mΩ
18	112.0V	0.043uA	128.9mΩ	112.0V	0.058uA	128.8mΩ
19	111.7V	0.049uA	128.4mΩ	111.7V	0.058uA	128.2mΩ
20	112.1V	0.041uA	128.8mΩ	112.3V	0.042uA	129.2mΩ
21	111.4V	0.041uA	129.0mΩ	111.9V	0.062uA	129.0mΩ
22	112.2V	0.055uA	128.2mΩ	112.2V	0.040uA	128.9mΩ
23	111.6V	0.059uA	129.0mΩ	112.3V	0.050uA	129.0mΩ
24	111.6V	0.053uA	129.1mΩ	112.2V	0.052uA	129.1mΩ
25	112.0V	0.043uA	129.3mΩ	111.9V	0.042uA	129.0mΩ
26	112.0V	0.056uA	128.8mΩ	112.0V	0.040uA	128.3mΩ
27	111.6V	0.047uA	129.0mΩ	112.3V	0.044uA	129.1mΩ
28	112.0V	0.053uA	128.8mΩ	112.2V	0.051uA	128.7mΩ
29	111.7V	0.042uA	128.9mΩ	111.5V	0.058uA	128.2mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 150℃, 1000Hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	111.9V	0.050uA	128.2mΩ	112.2V	0.046uA	128.5mΩ
31	112.0V	0.047uA	129.0mΩ	112.3V	0.040uA	128.8mΩ
32	111.6V	0.053uA	128.8mΩ	111.6V	0.052uA	128.9mΩ
33	112.3V	0.042uA	128.2mΩ	111.6V	0.060uA	128.8mΩ
34	112.0V	0.048uA	129.1mΩ	112.3V	0.057uA	129.3mΩ
35	111.5V	0.044uA	129.3mΩ	112.0V	0.058uA	128.9mΩ
36	111.8V	0.060uA	129.2mΩ	112.1V	0.049uA	128.9mΩ
37	111.4V	0.059uA	128.5mΩ	111.7V	0.059uA	128.3mΩ
38	111.6V	0.057uA	128.9mΩ	111.8V	0.050uA	129.0mΩ
39	111.6V	0.065uA	128.3mΩ	111.5V	0.040uA	129.3mΩ
40	112.2V	0.061uA	129.3mΩ	112.3V	0.053uA	129.2mΩ
41	112.1V	0.040uA	128.3mΩ	111.8V	0.062uA	128.5mΩ
42	111.9V	0.050uA	128.5mΩ	112.2V	0.052uA	129.4mΩ
43	112.3V	0.063uA	129.2mΩ	111.8V	0.040uA	128.3mΩ
44	111.9V	0.050uA	128.8mΩ	112.0V	0.040uA	128.3mΩ
45	111.6V	0.041uA	128.3mΩ	111.7V	0.040uA	129.0mΩ
46	111.7V	0.052uA	128.3mΩ	112.1V	0.065uA	128.9mΩ
47	111.5V	0.056uA	128.4mΩ	112.3V	0.042uA	129.1mΩ
48	112.1V	0.042uA	128.5mΩ	111.4V	0.064uA	128.3mΩ
49	112.1V	0.048uA	129.0mΩ	111.8V	0.055uA	128.9mΩ
50	112.2V	0.051uA	128.9mΩ	112.3V	0.061uA	128.8mΩ
51	111.9V	0.053uA	128.4mΩ	111.9V	0.060uA	128.2mΩ
52	112.4V	0.041uA	129.1mΩ	112.3V	0.051uA	129.0mΩ
53	111.7V	0.065uA	128.7mΩ	111.7V	0.056uA	129.2mΩ
54	112.2V	0.050uA	128.7mΩ	112.1V	0.055uA	129.2mΩ
55	111.7V	0.046uA	128.9mΩ	111.5V	0.059uA	128.4mΩ
56	111.7V	0.048uA	129.0mΩ	111.7V	0.062uA	128.4mΩ
57	112.2V	0.044uA	129.2mΩ	111.5V	0.053uA	129.4mΩ
58	111.4V	0.047uA	128.6mΩ	112.3V	0.058uA	128.3mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 150℃, 1000Hrs
Test Date: 2015.08.17 ~ 2015.09.29
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	112.3V	0.057uA	129.2mΩ	111.5V	0.052uA	128.6mΩ
60	112.1V	0.056uA	128.7mΩ	111.9V	0.052uA	129.3mΩ
61	112.4V	0.047uA	128.6mΩ	112.0V	0.043uA	128.8mΩ
62	111.6V	0.056uA	128.3mΩ	111.8V	0.043uA	128.6mΩ
63	112.1V	0.056uA	128.2mΩ	111.9V	0.062uA	128.2mΩ
64	111.7V	0.065uA	129.4mΩ	112.0V	0.041uA	129.1mΩ
65	111.8V	0.057uA	128.4mΩ	111.6V	0.061uA	129.2mΩ
66	111.5V	0.052uA	129.4mΩ	112.0V	0.056uA	129.1mΩ
67	111.6V	0.063uA	128.9mΩ	112.3V	0.057uA	128.2mΩ
68	111.6V	0.064uA	129.1mΩ	111.5V	0.060uA	129.1mΩ
69	111.8V	0.049uA	128.8mΩ	111.8V	0.049uA	129.2mΩ
70	111.6V	0.061uA	128.6mΩ	112.1V	0.043uA	128.6mΩ
71	112.1V	0.055uA	128.9mΩ	112.2V	0.040uA	128.4mΩ
72	112.2V	0.051uA	128.4mΩ	111.9V	0.047uA	128.5mΩ
73	111.8V	0.058uA	128.4mΩ	112.3V	0.062uA	129.0mΩ
74	112.2V	0.045uA	128.8mΩ	112.2V	0.055uA	129.3mΩ
75	112.2V	0.060uA	128.7mΩ	112.2V	0.043uA	128.7mΩ
76	112.1V	0.058uA	128.4mΩ	111.9V	0.058uA	129.1mΩ
77	112.1V	0.060uA	128.2mΩ	111.5V	0.065uA	128.7mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2015.08.17 ~ 2015.08.25
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	111.8V	0.051uA	128.6mΩ	112.1V	0.043uA	128.3mΩ
2	111.7V	0.063uA	128.6mΩ	111.7V	0.058uA	128.8mΩ
3	111.7V	0.045uA	128.9mΩ	111.4V	0.052uA	129.0mΩ
4	112.3V	0.046uA	128.2mΩ	111.8V	0.060uA	128.4mΩ
5	111.8V	0.046uA	129.2mΩ	111.4V	0.065uA	129.2mΩ
6	112.3V	0.049uA	128.9mΩ	111.8V	0.052uA	129.0mΩ
7	112.3V	0.055uA	128.8mΩ	111.9V	0.060uA	129.2mΩ
8	111.8V	0.047uA	128.8mΩ	112.0V	0.042uA	129.4mΩ
9	111.8V	0.063uA	128.6mΩ	112.3V	0.063uA	128.9mΩ
10	112.3V	0.043uA	128.8mΩ	112.2V	0.045uA	129.1mΩ
11	112.1V	0.041uA	129.2mΩ	112.2V	0.059uA	128.5mΩ
12	111.7V	0.059uA	128.7mΩ	111.5V	0.055uA	129.1mΩ
13	112.4V	0.060uA	129.0mΩ	112.1V	0.040uA	128.6mΩ
13	111.8V	0.044uA	128.8mΩ	111.7V	0.041uA	128.5mΩ
15	111.9V	0.044uA	129.0mΩ	111.5V	0.051uA	128.4mΩ
16	112.1V	0.041uA	128.3mΩ	112.4V	0.056uA	129.4mΩ
17	112.3V	0.058uA	128.7mΩ	112.0V	0.058uA	128.4mΩ
18	112.0V	0.054uA	129.2mΩ	111.9V	0.059uA	128.5mΩ
19	111.8V	0.058uA	128.6mΩ	111.6V	0.052uA	128.8mΩ
20	112.0V	0.061uA	128.9mΩ	111.8V	0.050uA	128.7mΩ
21	112.4V	0.045uA	128.8mΩ	112.2V	0.045uA	128.9mΩ
22	111.9V	0.056uA	128.7mΩ	111.7V	0.048uA	128.3mΩ
23	111.6V	0.049uA	129.2mΩ	112.2V	0.045uA	128.3mΩ
24	111.8V	0.047uA	128.3mΩ	112.0V	0.057uA	128.9mΩ
25	111.5V	0.047uA	129.2mΩ	112.0V	0.042uA	129.0mΩ
26	112.3V	0.062uA	129.0mΩ	111.7V	0.063uA	128.6mΩ
27	112.3V	0.052uA	129.4mΩ	112.2V	0.058uA	128.5mΩ
28	112.0V	0.062uA	128.5mΩ	111.9V	0.048uA	128.9mΩ
29	111.7V	0.047uA	129.1mΩ	111.9V	0.053uA	128.5mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2015.08.17 ~ 2015.08.25
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	112.4V	0.044uA	128.3mΩ	112.0V	0.045uA	129.2mΩ
31	112.3V	0.065uA	128.6mΩ	111.9V	0.055uA	129.3mΩ
32	112.0V	0.065uA	128.4mΩ	112.3V	0.041uA	128.9mΩ
33	112.0V	0.051uA	129.1mΩ	111.7V	0.050uA	128.5mΩ
34	111.8V	0.049uA	128.6mΩ	111.8V	0.054uA	129.4mΩ
35	112.1V	0.061uA	128.9mΩ	112.0V	0.061uA	128.4mΩ
36	111.9V	0.050uA	129.4mΩ	112.0V	0.055uA	129.3mΩ
37	111.6V	0.049uA	129.1mΩ	111.7V	0.049uA	129.0mΩ
38	112.4V	0.060uA	129.0mΩ	112.0V	0.053uA	129.0mΩ
39	112.0V	0.051uA	129.3mΩ	111.4V	0.057uA	128.2mΩ
40	112.3V	0.042uA	129.0mΩ	112.1V	0.062uA	128.9mΩ
41	111.4V	0.044uA	128.2mΩ	112.0V	0.055uA	129.2mΩ
42	111.8V	0.064uA	128.3mΩ	111.8V	0.043uA	128.6mΩ
43	112.3V	0.052uA	128.5mΩ	112.3V	0.051uA	129.2mΩ
44	111.7V	0.055uA	128.3mΩ	112.1V	0.052uA	128.2mΩ
45	112.0V	0.063uA	128.4mΩ	111.9V	0.040uA	128.2mΩ
46	112.2V	0.053uA	129.2mΩ	111.7V	0.054uA	128.8mΩ
47	112.3V	0.048uA	128.5mΩ	112.4V	0.051uA	129.2mΩ
48	111.8V	0.040uA	129.2mΩ	111.7V	0.054uA	128.9mΩ
49	112.1V	0.051uA	128.6mΩ	111.9V	0.055uA	128.4mΩ
50	111.5V	0.039uA	129.1mΩ	111.5V	0.061uA	129.0mΩ
51	112.2V	0.045uA	129.2mΩ	111.4V	0.057uA	128.6mΩ
52	111.6V	0.061uA	128.8mΩ	112.1V	0.051uA	129.2mΩ
53	111.4V	0.045uA	128.5mΩ	112.0V	0.042uA	129.0mΩ
54	111.5V	0.061uA	129.4mΩ	112.0V	0.061uA	129.2mΩ
55	112.2V	0.043uA	128.6mΩ	112.0V	0.051uA	129.3mΩ
56	112.3V	0.063uA	128.8mΩ	112.3V	0.054uA	129.3mΩ
57	112.1V	0.060uA	129.3mΩ	112.4V	0.044uA	128.4mΩ
58	112.1V	0.060uA	128.8mΩ	111.7V	0.051uA	129.3mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2015.08.17 ~ 2015.08.25
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	111.5V	0.055uA	129.1mΩ	112.0V	0.047uA	129.3mΩ
60	111.4V	0.049uA	128.9mΩ	112.1V	0.041uA	129.3mΩ
61	112.1V	0.056uA	128.3mΩ	112.3V	0.064uA	128.4mΩ
62	111.5V	0.048uA	129.4mΩ	111.9V	0.061uA	129.2mΩ
63	111.6V	0.044uA	128.6mΩ	111.9V	0.057uA	128.9mΩ
64	111.5V	0.045uA	128.7mΩ	112.2V	0.053uA	128.6mΩ
65	112.1V	0.060uA	128.7mΩ	112.1V	0.055uA	128.8mΩ
66	111.6V	0.049uA	128.9mΩ	111.7V	0.052uA	128.4mΩ
67	112.3V	0.062uA	128.7mΩ	111.5V	0.052uA	128.3mΩ
68	111.6V	0.058uA	128.7mΩ	112.2V	0.058uA	129.2mΩ
69	111.5V	0.059uA	129.4mΩ	111.7V	0.052uA	128.4mΩ
70	112.3V	0.064uA	129.2mΩ	112.1V	0.063uA	128.8mΩ
71	111.8V	0.059uA	129.0mΩ	112.1V	0.042uA	129.2mΩ
72	112.4V	0.045uA	129.0mΩ	111.7V	0.059uA	128.7mΩ
73	111.8V	0.040uA	128.8mΩ	112.1V	0.044uA	129.2mΩ
74	112.4V	0.065uA	128.9mΩ	111.5V	0.049uA	129.2mΩ
75	111.7V	0.061uA	129.3mΩ	112.2V	0.050uA	128.5mΩ
76	112.0V	0.053uA	129.1mΩ	112.3V	0.058uA	128.8mΩ
77	112.1V	0.046uA	128.7mΩ	111.6V	0.049uA	129.2mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2015.08.17 ~ 2015.10.08
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	111.6V	0.061uA	129.2mΩ	112.3V	0.049uA	128.7mΩ
2	112.3V	0.041uA	129.2mΩ	112.2V	0.050uA	129.2mΩ
3	111.8V	0.042uA	128.6mΩ	111.8V	0.059uA	129.2mΩ
4	112.3V	0.061uA	128.4mΩ	111.5V	0.060uA	128.4mΩ
5	111.6V	0.056uA	129.0mΩ	111.4V	0.060uA	128.8mΩ
6	111.6V	0.041uA	129.3mΩ	112.3V	0.048uA	128.8mΩ
7	112.0V	0.050uA	128.7mΩ	112.2V	0.058uA	128.6mΩ
8	112.3V	0.050uA	128.8mΩ	111.5V	0.045uA	128.2mΩ
9	111.5V	0.064uA	128.8mΩ	111.7V	0.039uA	128.7mΩ
10	111.5V	0.048uA	128.9mΩ	112.3V	0.058uA	128.6mΩ
11	111.6V	0.062uA	128.9mΩ	112.0V	0.049uA	128.8mΩ
12	111.9V	0.052uA	129.0mΩ	111.9V	0.062uA	129.0mΩ
13	111.9V	0.041uA	128.5mΩ	111.5V	0.056uA	129.0mΩ
13	111.5V	0.040uA	129.0mΩ	111.7V	0.062uA	128.6mΩ
15	111.7V	0.054uA	129.1mΩ	112.4V	0.058uA	129.4mΩ
16	111.9V	0.046uA	129.3mΩ	112.3V	0.060uA	129.1mΩ
17	111.8V	0.058uA	128.6mΩ	112.0V	0.048uA	128.9mΩ
18	112.2V	0.052uA	128.5mΩ	111.9V	0.048uA	128.5mΩ
19	111.4V	0.063uA	129.3mΩ	112.1V	0.051uA	129.1mΩ
20	112.2V	0.057uA	128.6mΩ	112.3V	0.056uA	129.2mΩ
21	112.0V	0.054uA	128.6mΩ	112.4V	0.043uA	128.4mΩ
22	111.9V	0.045uA	129.2mΩ	111.6V	0.041uA	128.5mΩ
23	111.7V	0.053uA	129.0mΩ	112.1V	0.057uA	129.2mΩ
24	112.2V	0.054uA	128.8mΩ	111.8V	0.058uA	128.9mΩ
25	111.7V	0.048uA	128.3mΩ	112.2V	0.047uA	129.3mΩ
26	111.7V	0.046uA	129.0mΩ	111.8V	0.061uA	128.8mΩ
27	112.1V	0.057uA	128.9mΩ	111.6V	0.044uA	128.6mΩ
28	111.7V	0.056uA	128.6mΩ	112.1V	0.059uA	128.5mΩ
29	111.4V	0.055uA	128.8mΩ	111.6V	0.058uA	129.3mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2015.08.17 ~ 2015.10.08
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	111.4V	0.055uA	128.4mΩ	112.2V	0.059uA	129.3mΩ
31	112.2V	0.057uA	129.2mΩ	112.1V	0.054uA	128.4mΩ
32	111.8V	0.048uA	128.8mΩ	112.0V	0.059uA	128.7mΩ
33	111.4V	0.059uA	128.4mΩ	111.8V	0.041uA	128.6mΩ
34	111.7V	0.041uA	128.3mΩ	112.1V	0.043uA	129.2mΩ
35	111.9V	0.052uA	128.6mΩ	112.3V	0.051uA	128.9mΩ
36	111.8V	0.048uA	128.7mΩ	111.8V	0.040uA	129.3mΩ
37	112.0V	0.054uA	128.8mΩ	111.4V	0.054uA	128.9mΩ
38	111.9V	0.060uA	129.4mΩ	112.2V	0.057uA	128.6mΩ
39	112.0V	0.053uA	129.2mΩ	112.0V	0.047uA	128.5mΩ
40	112.2V	0.063uA	129.1mΩ	112.2V	0.063uA	128.3mΩ
41	111.7V	0.052uA	128.3mΩ	112.2V	0.060uA	128.4mΩ
42	112.0V	0.060uA	128.8mΩ	111.6V	0.065uA	129.2mΩ
43	112.3V	0.061uA	128.6mΩ	111.9V	0.056uA	128.3mΩ
44	112.4V	0.044uA	128.2mΩ	111.6V	0.062uA	128.5mΩ
45	111.7V	0.051uA	128.8mΩ	112.2V	0.044uA	128.9mΩ
46	111.4V	0.056uA	129.4mΩ	111.4V	0.041uA	128.3mΩ
47	112.0V	0.056uA	129.3mΩ	112.0V	0.051uA	128.4mΩ
48	111.8V	0.052uA	128.8mΩ	111.5V	0.041uA	128.5mΩ
49	111.6V	0.056uA	128.8mΩ	111.4V	0.053uA	129.4mΩ
50	112.4V	0.045uA	129.0mΩ	111.8V	0.051uA	128.6mΩ
51	112.3V	0.056uA	129.1mΩ	112.3V	0.056uA	129.2mΩ
52	111.6V	0.046uA	128.5mΩ	111.8V	0.047uA	128.5mΩ
53	112.0V	0.053uA	128.7mΩ	112.4V	0.055uA	129.1mΩ
54	112.4V	0.051uA	128.2mΩ	112.0V	0.042uA	128.7mΩ
55	111.9V	0.051uA	128.9mΩ	111.7V	0.053uA	128.4mΩ
56	111.9V	0.057uA	128.8mΩ	111.5V	0.061uA	128.3mΩ
57	111.4V	0.045uA	129.1mΩ	111.8V	0.053uA	129.2mΩ
58	112.2V	0.045uA	128.9mΩ	111.6V	0.063uA	129.0mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2015.08.17 ~ 2015.10.08
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	112.0V	0.051uA	128.7mΩ	111.8V	0.047uA	128.8mΩ
60	111.6V	0.063uA	128.2mΩ	111.5V	0.058uA	128.6mΩ
61	111.7V	0.048uA	128.6mΩ	111.7V	0.056uA	129.4mΩ
62	112.3V	0.056uA	129.0mΩ	112.2V	0.053uA	129.4mΩ
63	111.6V	0.061uA	129.2mΩ	112.2V	0.054uA	128.9mΩ
64	111.8V	0.044uA	128.4mΩ	112.0V	0.040uA	128.9mΩ
65	111.6V	0.050uA	128.5mΩ	111.7V	0.054uA	128.9mΩ
66	112.3V	0.053uA	129.2mΩ	111.9V	0.042uA	129.3mΩ
67	112.1V	0.059uA	128.4mΩ	111.6V	0.059uA	129.0mΩ
68	111.5V	0.048uA	128.7mΩ	111.5V	0.049uA	129.3mΩ
69	111.7V	0.051uA	129.1mΩ	111.7V	0.062uA	128.7mΩ
70	112.4V	0.049uA	128.4mΩ	112.1V	0.063uA	129.3mΩ
71	111.5V	0.061uA	128.7mΩ	111.7V	0.048uA	128.7mΩ
72	111.7V	0.056uA	129.3mΩ	111.6V	0.045uA	128.6mΩ
73	111.8V	0.057uA	129.0mΩ	112.2V	0.046uA	128.6mΩ
74	111.9V	0.053uA	128.7mΩ	111.5V	0.061uA	129.3mΩ
75	111.7V	0.056uA	128.3mΩ	112.3V	0.048uA	129.2mΩ
76	112.2V	0.057uA	129.1mΩ	112.0V	0.055uA	129.4mΩ
77	112.2V	0.063uA	129.0mΩ	112.3V	0.060uA	128.9mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	111.8V	0.046uA	128.3mΩ	111.6V	0.051uA	128.2mΩ
2	112.0V	0.049uA	129.0mΩ	111.8V	0.057uA	128.6mΩ
3	111.8V	0.058uA	128.9mΩ	111.5V	0.061uA	128.2mΩ
4	111.7V	0.047uA	128.4mΩ	111.8V	0.060uA	128.5mΩ
5	111.9V	0.044uA	128.6mΩ	112.0V	0.058uA	128.7mΩ
6	111.5V	0.041uA	128.8mΩ	112.4V	0.052uA	128.7mΩ
7	112.3V	0.058uA	128.5mΩ	111.7V	0.045uA	128.8mΩ
8	112.4V	0.064uA	128.3mΩ	112.0V	0.054uA	128.8mΩ
9	112.0V	0.049uA	128.6mΩ	111.7V	0.041uA	128.8mΩ
10	111.8V	0.060uA	128.6mΩ	112.0V	0.048uA	129.1mΩ
11	112.1V	0.047uA	128.6mΩ	112.3V	0.054uA	128.7mΩ
12	112.3V	0.063uA	129.1mΩ	111.8V	0.058uA	128.9mΩ
13	111.7V	0.049uA	128.8mΩ	111.7V	0.055uA	128.8mΩ
13	112.3V	0.051uA	128.7mΩ	111.7V	0.048uA	128.8mΩ
15	112.3V	0.057uA	128.4mΩ	111.4V	0.061uA	128.8mΩ
16	112.2V	0.043uA	128.4mΩ	111.8V	0.059uA	129.2mΩ
17	112.0V	0.060uA	129.2mΩ	112.1V	0.061uA	128.9mΩ
18	111.7V	0.044uA	128.3mΩ	112.0V	0.060uA	128.8mΩ
19	111.8V	0.051uA	129.0mΩ	112.3V	0.052uA	128.4mΩ
20	111.9V	0.050uA	128.7mΩ	111.7V	0.048uA	128.5mΩ
21	111.6V	0.056uA	128.3mΩ	111.7V	0.045uA	129.1mΩ
22	111.4V	0.055uA	129.2mΩ	111.7V	0.052uA	129.0mΩ
23	112.1V	0.055uA	128.6mΩ	112.1V	0.063uA	128.9mΩ
24	112.0V	0.058uA	129.0mΩ	111.7V	0.052uA	128.3mΩ
25	111.7V	0.061uA	129.0mΩ	111.9V	0.065uA	128.9mΩ
26	111.8V	0.048uA	128.7mΩ	111.8V	0.048uA	129.3mΩ
27	112.3V	0.064uA	128.5mΩ	111.7V	0.051uA	128.3mΩ
28	111.8V	0.045uA	128.3mΩ	112.4V	0.040uA	128.6mΩ
29	112.1V	0.061uA	129.1mΩ	111.5V	0.040uA	129.1mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	111.9V	0.044uA	129.0mΩ	111.8V	0.058uA	129.3mΩ
31	111.7V	0.062uA	129.1mΩ	111.7V	0.047uA	128.5mΩ
32	112.1V	0.052uA	128.7mΩ	111.9V	0.040uA	128.6mΩ
33	112.0V	0.044uA	128.4mΩ	111.6V	0.063uA	128.6mΩ
34	112.4V	0.051uA	128.4mΩ	111.9V	0.045uA	129.2mΩ
35	111.4V	0.043uA	128.9mΩ	111.9V	0.064uA	128.7mΩ
36	111.4V	0.042uA	128.5mΩ	111.7V	0.050uA	128.9mΩ
37	112.0V	0.049uA	128.9mΩ	112.3V	0.058uA	128.8mΩ
38	111.6V	0.048uA	128.7mΩ	112.1V	0.042uA	129.0mΩ
39	111.4V	0.051uA	129.3mΩ	111.8V	0.041uA	129.2mΩ
40	112.1V	0.059uA	129.2mΩ	112.0V	0.053uA	128.8mΩ
41	112.1V	0.065uA	129.0mΩ	111.5V	0.064uA	128.2mΩ
42	111.8V	0.042uA	128.6mΩ	111.9V	0.045uA	128.7mΩ
43	111.5V	0.057uA	128.9mΩ	112.3V	0.057uA	129.0mΩ
44	112.0V	0.063uA	128.9mΩ	111.9V	0.064uA	129.0mΩ
45	112.0V	0.048uA	128.5mΩ	111.7V	0.055uA	128.4mΩ
46	111.5V	0.053uA	128.7mΩ	112.1V	0.051uA	128.7mΩ
47	111.6V	0.051uA	128.2mΩ	111.8V	0.041uA	129.1mΩ
48	111.9V	0.048uA	129.1mΩ	112.4V	0.054uA	129.3mΩ
49	112.0V	0.060uA	129.0mΩ	112.0V	0.062uA	128.9mΩ
50	111.9V	0.059uA	128.9mΩ	111.5V	0.050uA	128.7mΩ
51	111.9V	0.044uA	128.3mΩ	111.4V	0.055uA	128.9mΩ
52	111.8V	0.050uA	129.0mΩ	111.6V	0.043uA	128.6mΩ
53	112.1V	0.060uA	129.1mΩ	111.7V	0.051uA	129.0mΩ
54	111.9V	0.058uA	128.4mΩ	112.0V	0.057uA	128.5mΩ
55	111.5V	0.052uA	128.8mΩ	112.2V	0.046uA	128.9mΩ
56	112.0V	0.046uA	128.3mΩ	112.1V	0.064uA	129.3mΩ
57	111.9V	0.064uA	129.0mΩ	112.3V	0.058uA	128.4mΩ
58	111.5V	0.048uA	128.6mΩ	111.6V	0.040uA	128.8mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	111.4V	0.055uA	128.6mΩ	111.8V	0.044uA	129.0mΩ
60	111.7V	0.040uA	129.1mΩ	111.5V	0.048uA	129.2mΩ
61	111.6V	0.063uA	128.7mΩ	111.9V	0.040uA	128.4mΩ
62	111.9V	0.044uA	129.3mΩ	112.1V	0.055uA	129.0mΩ
63	111.6V	0.063uA	128.7mΩ	111.5V	0.056uA	128.7mΩ
64	111.7V	0.045uA	128.3mΩ	112.0V	0.063uA	128.6mΩ
65	112.2V	0.057uA	129.0mΩ	111.7V	0.049uA	129.4mΩ
66	111.8V	0.043uA	128.4mΩ	112.4V	0.052uA	129.2mΩ
67	111.9V	0.048uA	129.3mΩ	112.4V	0.045uA	129.4mΩ
68	112.0V	0.053uA	129.4mΩ	111.6V	0.056uA	128.7mΩ
69	112.0V	0.056uA	128.3mΩ	111.6V	0.062uA	128.6mΩ
70	111.7V	0.043uA	128.3mΩ	112.1V	0.056uA	128.3mΩ
71	112.2V	0.047uA	128.5mΩ	111.5V	0.064uA	128.5mΩ
72	111.7V	0.044uA	129.3mΩ	111.4V	0.042uA	128.4mΩ
73	111.6V	0.057uA	128.8mΩ	111.8V	0.059uA	128.7mΩ
74	112.3V	0.047uA	128.4mΩ	111.5V	0.043uA	129.4mΩ
75	111.8V	0.062uA	128.8mΩ	111.6V	0.043uA	129.3mΩ
76	112.0V	0.051uA	129.4mΩ	111.5V	0.044uA	129.1mΩ
77	112.0V	0.062uA	128.3mΩ	112.4V	0.045uA	129.2mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	111.7V	0.062uA	129.3mΩ	111.7V	0.057uA	129.3mΩ
2	111.5V	0.064uA	128.4mΩ	112.2V	0.044uA	129.1mΩ
3	111.5V	0.053uA	129.2mΩ	112.0V	0.060uA	129.3mΩ
4	112.2V	0.042uA	128.5mΩ	112.0V	0.045uA	129.2mΩ
5	111.7V	0.049uA	129.2mΩ	112.4V	0.058uA	128.9mΩ
6	111.5V	0.057uA	129.0mΩ	112.2V	0.041uA	128.2mΩ
7	112.1V	0.050uA	128.7mΩ	112.1V	0.042uA	128.9mΩ
8	111.8V	0.060uA	128.3mΩ	111.9V	0.045uA	128.6mΩ
9	111.7V	0.051uA	129.3mΩ	112.1V	0.052uA	128.8mΩ
10	111.6V	0.050uA	128.9mΩ	111.8V	0.052uA	129.3mΩ
11	112.1V	0.053uA	129.1mΩ	112.2V	0.054uA	128.6mΩ
12	111.6V	0.041uA	128.7mΩ	111.5V	0.046uA	128.8mΩ
13	111.7V	0.049uA	129.1mΩ	111.9V	0.050uA	128.8mΩ
13	111.8V	0.045uA	129.1mΩ	111.9V	0.060uA	129.1mΩ
15	112.3V	0.061uA	128.9mΩ	111.7V	0.056uA	128.6mΩ
16	111.6V	0.056uA	128.3mΩ	111.6V	0.058uA	128.9mΩ
17	111.5V	0.061uA	128.2mΩ	111.9V	0.062uA	128.2mΩ
18	112.4V	0.050uA	129.0mΩ	111.8V	0.053uA	128.6mΩ
19	112.0V	0.059uA	128.3mΩ	112.1V	0.042uA	128.3mΩ
20	111.9V	0.054uA	128.7mΩ	111.9V	0.046uA	129.0mΩ
21	111.7V	0.051uA	128.5mΩ	112.4V	0.049uA	129.3mΩ
22	112.3V	0.048uA	128.4mΩ	111.8V	0.058uA	128.5mΩ
23	111.9V	0.058uA	129.2mΩ	111.9V	0.061uA	128.3mΩ
24	112.0V	0.046uA	128.3mΩ	112.0V	0.058uA	128.2mΩ
25	111.9V	0.057uA	129.0mΩ	112.4V	0.061uA	129.0mΩ
26	112.3V	0.045uA	128.7mΩ	111.6V	0.049uA	128.4mΩ
27	112.1V	0.062uA	128.8mΩ	112.3V	0.055uA	129.0mΩ
28	112.0V	0.042uA	128.8mΩ	112.3V	0.055uA	128.5mΩ
29	111.8V	0.048uA	128.3mΩ	111.9V	0.055uA	129.1mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	112.0V	0.045uA	129.2mΩ	112.0V	0.042uA	128.3mΩ
31	112.3V	0.065uA	128.8mΩ	111.6V	0.054uA	128.4mΩ
32	111.8V	0.053uA	128.3mΩ	112.4V	0.044uA	128.6mΩ
33	112.1V	0.062uA	128.2mΩ	112.4V	0.047uA	128.6mΩ
34	111.9V	0.042uA	128.8mΩ	111.6V	0.055uA	128.2mΩ
35	112.3V	0.058uA	129.2mΩ	111.4V	0.057uA	128.6mΩ
36	112.1V	0.062uA	128.8mΩ	111.9V	0.051uA	129.4mΩ
37	112.1V	0.053uA	128.4mΩ	112.3V	0.064uA	129.2mΩ
38	111.5V	0.050uA	129.1mΩ	112.2V	0.063uA	129.0mΩ
39	111.4V	0.040uA	128.5mΩ	112.3V	0.050uA	128.6mΩ
40	112.4V	0.055uA	129.0mΩ	112.3V	0.043uA	129.3mΩ
41	112.3V	0.060uA	129.2mΩ	111.7V	0.041uA	129.0mΩ
42	111.7V	0.056uA	128.4mΩ	111.5V	0.060uA	128.8mΩ
43	112.0V	0.045uA	128.4mΩ	112.0V	0.045uA	129.2mΩ
44	112.3V	0.049uA	128.5mΩ	111.4V	0.048uA	128.3mΩ
45	111.6V	0.064uA	128.7mΩ	111.8V	0.047uA	129.2mΩ
46	112.4V	0.041uA	128.4mΩ	112.3V	0.062uA	129.3mΩ
47	111.9V	0.054uA	128.6mΩ	111.6V	0.063uA	129.3mΩ
48	112.2V	0.061uA	128.4mΩ	111.7V	0.053uA	129.4mΩ
49	111.9V	0.048uA	128.3mΩ	111.9V	0.047uA	128.8mΩ
50	112.3V	0.047uA	128.9mΩ	112.4V	0.061uA	129.1mΩ
51	112.0V	0.040uA	128.6mΩ	111.9V	0.052uA	128.8mΩ
52	112.2V	0.041uA	128.9mΩ	111.8V	0.057uA	128.2mΩ
53	112.1V	0.041uA	128.9mΩ	111.8V	0.046uA	128.4mΩ
54	111.9V	0.043uA	128.9mΩ	112.0V	0.064uA	128.2mΩ
55	111.5V	0.048uA	128.9mΩ	111.5V	0.053uA	129.1mΩ
56	112.0V	0.053uA	128.5mΩ	112.1V	0.061uA	128.3mΩ
57	111.9V	0.057uA	128.4mΩ	111.7V	0.050uA	129.0mΩ
58	111.7V	0.054uA	129.1mΩ	111.7V	0.047uA	128.5mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2015.08.25 ~ 2015.10.06
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	112.3V	0.060uA	129.0mΩ	111.4V	0.049uA	128.4mΩ
60	112.0V	0.054uA	128.9mΩ	112.0V	0.040uA	129.3mΩ
61	111.6V	0.048uA	128.3mΩ	111.5V	0.062uA	129.3mΩ
62	111.5V	0.060uA	128.6mΩ	111.5V	0.041uA	128.5mΩ
63	111.8V	0.047uA	129.3mΩ	111.7V	0.059uA	128.5mΩ
64	112.0V	0.062uA	128.9mΩ	111.7V	0.049uA	128.7mΩ
65	111.6V	0.054uA	128.4mΩ	112.3V	0.040uA	128.6mΩ
66	111.8V	0.040uA	128.8mΩ	112.2V	0.047uA	128.3mΩ
67	112.3V	0.045uA	128.5mΩ	111.5V	0.064uA	128.7mΩ
68	111.8V	0.063uA	128.7mΩ	111.7V	0.055uA	129.1mΩ
69	111.5V	0.058uA	129.1mΩ	111.5V	0.044uA	128.4mΩ
70	111.7V	0.049uA	129.2mΩ	111.6V	0.045uA	129.0mΩ
71	111.9V	0.055uA	128.9mΩ	112.1V	0.043uA	128.6mΩ
72	111.7V	0.057uA	128.4mΩ	111.7V	0.051uA	128.6mΩ
73	112.1V	0.044uA	129.0mΩ	111.8V	0.053uA	129.1mΩ
74	112.4V	0.043uA	128.3mΩ	111.6V	0.048uA	128.4mΩ
75	112.2V	0.042uA	128.8mΩ	112.0V	0.062uA	129.0mΩ
76	112.3V	0.059uA	129.1mΩ	111.7V	0.040uA	128.5mΩ
77	111.8V	0.054uA	129.1mΩ	111.5V	0.044uA	129.1mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Solderability Test Data

Report No : T151008-113
Part No : SSM0410
Test Equipment: JUNO Test System DTS-1000
Test Condition : 100V <V(BR)DSS @ID=1mA ；IDSS < 10μA@VDS=100V
RDS(ON) < 220mΩ@VGS=10V, ID=2.6A
Test Condition: 245℃ ± 5℃, 5Sec
Test Date: 2015.10.08
Test Standard : JESD22 STANDER Method-B102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	111.8V	0.065uA	129.0mΩ	111.6V	0.057uA	129.1mΩ
2	112.2V	0.057uA	129.0mΩ	111.6V	0.056uA	129.3mΩ
3	111.8V	0.040uA	129.4mΩ	112.0V	0.043uA	128.8mΩ
4	111.5V	0.040uA	129.1mΩ	112.1V	0.056uA	129.0mΩ
5	112.0V	0.064uA	128.5mΩ	111.7V	0.049uA	128.6mΩ
6	112.0V	0.046uA	129.4mΩ	112.3V	0.042uA	128.6mΩ
7	112.1V	0.043uA	128.7mΩ	111.5V	0.043uA	129.3mΩ
8	112.0V	0.051uA	128.7mΩ	112.0V	0.058uA	128.5mΩ
9	112.1V	0.042uA	129.0mΩ	112.3V	0.055uA	128.3mΩ
10	112.1V	0.059uA	129.2mΩ	111.5V	0.058uA	128.2mΩ

Made By: King Huang

Approval: Peter Yang